# 1 Electrical ratings

Symbol	Parameter	Value	Unit
V <sub>CES</sub>	Collector-emitter voltage (V <sub>GE</sub> = 0)	650	V
۱ <sub>C</sub>	Continuous collector current at T <sub>C</sub> = 25 °C	80 <sup>(1)</sup>	А
۱ <sub>C</sub>	Continuous collector current at T <sub>C</sub> = 100 °C	60	А
I <sub>CP</sub> <sup>(2)</sup>	Pulsed collector current	240	А
V <sub>GE</sub>	Gate-emitter voltage	±20	V
١ <sub>F</sub>	Continuous forward current at $T_C = 25 \text{ °C}$	80 <sup>(1)</sup>	А
١ <sub>F</sub>	Continuous forward current at $T_C = 100 \text{ °C}$	60	А
I <sub>FP</sub> <sup>(2)</sup>	Pulsed forward current	240	А
P <sub>TOT</sub>	Total dissipation at $T_{C} = 25 \text{ °C}$	375	W
T <sub>STG</sub>	Storage temperature range	- 55 to 150	°C
TJ	Operating junction temperature	- 40 to 175	°C

### Table 2. Absolute maximum ratings

1. Current level is limited by bond wires

2. Pulse width limited by maximum junction temperature and turn-off within RBSOA

Table 3. Thermal data

Symbol	Parameter	Value	Unit
R <sub>thJC</sub>	Thermal resistance junction-case IGBT	0.4	°C/W
R <sub>thJC</sub>	Thermal resistance junction-case diode	1.14	°C/W
R <sub>thJA</sub>	Thermal resistance junction-ambient	50	°C/W



## 2 Electrical characteristics

 $T_J = 25$  °C unless otherwise specified.

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
V <sub>(BR)CES</sub>	Collector-emitter breakdown voltage (V <sub>GE</sub> = 0)	I <sub>C</sub> = 2 mA	650			V
		V <sub>GE</sub> = 15 V, I <sub>C</sub> = 60 A		1.65		
V <sub>CE(sat)</sub>	Collector-emitter saturation voltage	V <sub>GE</sub> = 15 V, I <sub>C</sub> = 60 A T <sub>J</sub> = 125 °C		1.8		V
	voluge	V <sub>GE</sub> = 15 V, I <sub>C</sub> = 60 A T <sub>J</sub> = 175 °C		1.9		
		I <sub>F</sub> = 60 A		2	TBD	V
V <sub>F</sub>	Forward on-voltage	I <sub>F</sub> = 60 A T <sub>J</sub> = 125 °C		1.7		V
		I <sub>F</sub> = 60 A T <sub>J</sub> = 175 °C		1.6		V
V <sub>GE(th)</sub>	Gate threshold voltage	$V_{CE} = V_{GE}, I_C = 1 \text{ mA}$		6.0		V
I <sub>CES</sub>	Collector cut-off current $(V_{GE} = 0)$	V <sub>CE</sub> = 650 V			25	μΑ
I <sub>GES</sub>	Gate-emitter leakage current (V <sub>CE</sub> = 0)	V <sub>GE</sub> = ± 20 V			250	nA

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
C <sub>ies</sub>	Input capacitance		-	7900	-	pF
C <sub>oes</sub>	Output capacitance	V <sub>CE</sub> = 25 V, f = 1 MHz, V <sub>GE</sub> = 0	-	TBD	-	pF
C <sub>res</sub>	Reverse transfer capacitance		-	TBD	-	pF
Qg	Total gate charge		-	340	-	nC
Q <sub>ge</sub>	Gate-emitter charge	V <sub>CC</sub> = 520 V, I <sub>C</sub> = 60 A, V <sub>GE</sub> = 15 V, see <i>Figure 3</i>	-	TBD	-	nC
Q <sub>gc</sub>	Gate-collector charge	GL - ,	-	TBD	-	nC



Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
t <sub>d(on)</sub>	Turn-on delay time		-	TBD		ns
t <sub>r</sub>	Current rise time		-	TBD	-	ns
(di/dt) <sub>on</sub>	Turn-on current slope		-	TBD		A/µs
t <sub>d(off)</sub>	Turn-off delay time	$V_{CE} = 400 \text{ V}, \text{ I}_{C} = 60 \text{ A},$ - $R_{G} = 5 \Omega, \text{ V}_{GE} = 15 \text{ V},$		TBD		ns
t <sub>f</sub>	Current fall time	$r_{G} = 3.22, v_{GE} = 13.0,$ see <i>Figure</i> 2	-	TBD	-	ns
E <sub>on</sub> <sup>(1)</sup>	Turn-on switching losses		-	0.8	-	mJ
$E_{off}^{(2)}$	Turn-off switching losses		-	0.65	-	mJ
E <sub>ts</sub>	Total switching losses		-	1.45	-	mJ
t <sub>d(on)</sub>	Turn-on delay time		-	TBD		ns
t <sub>r</sub>	Current rise time		-	TBD	-	ns
(di/dt) <sub>on</sub>	Turn-on current slope		-	TBD		A/µs
t <sub>d(off)</sub>	Turn-off delay time	$V_{CE} = 400 \text{ V}, \text{ I}_{C} = 60 \text{ A},$		TBD		ns
t <sub>f</sub>	Current fall time	$-R_G = 5 \Omega$ , V <sub>GE</sub> = 15 V, T <sub>J</sub> = 175 °C, see <i>Figure</i> 2	-	TBD	-	ns
E <sub>on</sub> <sup>(1)</sup>	Turn-on switching losses		-	1.6	-	mJ
$E_{off}^{(2)}$	Turn-off switching losses		-	1.25	-	mJ
E <sub>ts</sub>	Total switching losses		-	2.85	-	mJ

Table 6. IGBT switch	ing characteristics	(inductive load)
	ing characteristics	(muucuve ioau)

1. Energy losses include reverse recovery of the diode.

2. Turn-off losses include also the tail of the collector current.

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
t <sub>rr</sub>	Reverse recovery time		-	TBD	-	ns
Q <sub>rr</sub>	Reverse recovery charge		-	TBD	-	nC
I <sub>rrm</sub>	Reverse recovery current	I <sub>F</sub> = 60 A, V <sub>R</sub> = 400 V, R <sub>G</sub> = 5 Ω, V <sub>GF</sub> = 15 V,	-	TBD	-	А
dI <sub>rr/</sub> /dt	Peak rate of fall of reverse recovery current during $t_b$	erse see <i>Figure 2</i> - TE	TBD	-	A/µs	
E <sub>rr</sub>	Reverse recovery energy		-	TBD	-	μJ
t <sub>rr</sub>	Reverse recovery time		-	TBD	-	ns
Q <sub>rr</sub>	Reverse recovery charge	]	-	TBD	-	nC
I <sub>rrm</sub>	Reverse recovery current	I <sub>F</sub> = 60 A, V <sub>R</sub> = 400 V, R <sub>G</sub> = 5 Ω, V <sub>GE</sub> = 15 V,	-	TBD	-	А
dI <sub>rr/</sub> /dt	Peak rate of fall of reverse recovery current during t <sub>b</sub>	$T_J = 175 \text{ °C}$ , see <i>Figure 2</i>	-	TBD	-	A/µs
E <sub>rr</sub>	Reverse recovery energy	]	-	TBD	-	μJ



o<sup>V</sup>cc

1KΩ

V G

AM01505v1

Figure 3. Gate charge test circuit

47Κ Ω

1KΩ

=100nF

́ D.U.T.

12V

 $V_i = 20V = V_{GMAX}$ 

2200 #F

1K Ω

I<sub>G</sub>=CONST

Ć 47K Ω

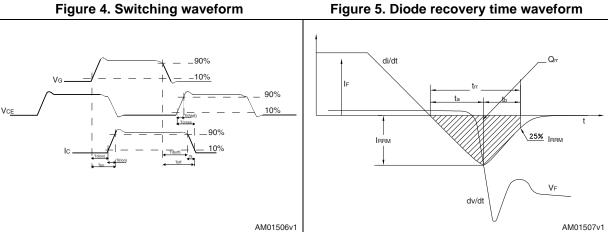
2.7ΚΩ

#### 3 **Test circuits**

switching 6 A ٠A С L=100µH G 1000 3.3 ΎВ  $\mu$  F  $\mu$ F  $V_{CC}$ G D.U.T. Ε  $R_{G}$ AM01504v1

Figure 2. Test circuit for inductive load

### Figure 4. Switching waveform



. Ρw



## 4 Package mechanical data

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK<sup>®</sup> packages, depending on their level of environmental compliance. ECOPACK<sup>®</sup> specifications, grade definitions and product status are available at: www.st.com. ECOPACK is an ST trademark.

Dim.		mm.	
	Min.	Тур.	Max.
А	4.85		5.15
A1	2.20		2.60
b	1.0		1.40
b1	2.0		2.40
b2	3.0		3.40
С	0.40		0.80
D	19.85		20.15
E	15.45		15.75
е	5.30	5.45	5.60
L	14.20		14.80
L1	3.70		4.30
L2		18.50	
ØP	3.55		3.65
ØR	4.50		5.50
S	5.30	5.50	5.70

Table 8. TO-247 mechanical data



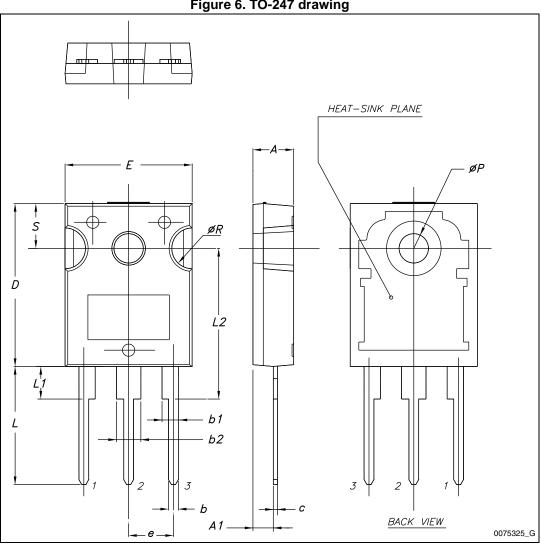


Figure 6. TO-247 drawing



Dim		mm	
Dim. —	Min.	Тур.	Max.
А	4.60		5
A1	1.45	1.50	1.65
A2	1.20	1.40	1.60
b	0.80	1	1.20
b1	1.80		2.20
b2	2.80		3.20
С	0.55	0.60	0.75
D	19.70	19.90	20.10
D1		13.90	
E	15.40		15.80
E1		13.60	
E2		9.60	
е	5.15	5.45	5.75
L	19.50	20	20.50
L1		3.50	
L2	18.20	18.40	18.60
øP	3.10		3.30
Q		5	
Q1		3.80	

Table 9. TO-3P mechanical data



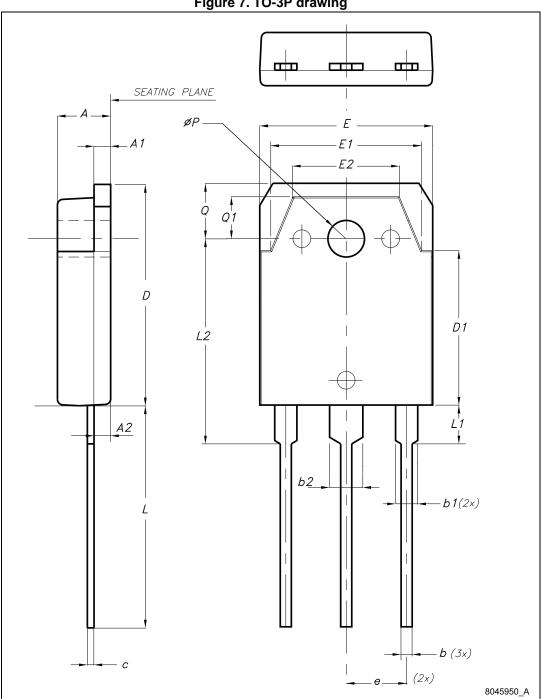


Figure 7. TO-3P drawing



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### 5 **Revision history**

Date	Revision	Changes
12-Mar-2013	1	Initial release.



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